

6/26/2006



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IFW  
LEE 2613  
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1 Inventor: Chulhee Lee  
2 Application No.: 10/082,081 Art Unit: 2613  
3 Filing Date: 02/26/2003 Examiner: Dave Czekaj  
4 **Title:** Methods for objective measurement of video quality

5 **AMENDMENT B**

6 Commissioner for Patents  
7 P. O. Box 1450  
8 Alexandria, Virginia 22313-1450  
9 USA

10 Sir:

11 In the Office Action dated May 3, 2006, it is stated:

- 12 I. Claims 6-7, drawn to measuring video quality using a wavelet transform,  
13 classified in class 375, subclass 240.19.  
14 II. Claims 8-9, drawn to computing spatial and temporal frequency differences,  
15 classified in class 348, subclass 425.1.

16 In response to the Office Action, the Applicant elects Option I with traverse. The Applicant  
17 believes that all the claims should be classified in the same class. Detailed arguments are  
18 provided in the following remarks.

19 The Examiner further noted an error in Claim 9. Accordingly, Claim 9 is cancelled and new  
20 Claim 10 is added.

21 The applicant believes that the Examiner will now find the claims of this application  
22 allowable. Favorable reconsideration of the application is courteously requested.

23 Respectively submitted,

24 Chulhee Lee

25 June 26, 2006  
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